EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	657	(714/42).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 14:03
S54	2	("6249893").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 20:25
S55	443	microcontroller with (defect error fault fail$4) with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 20:26
S56	199	microcontroller with (defect error fault fail$4) with (stor$4 log) with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 20:39
S57	36	microcontroller with (stor$4 log) with (defect error fault fail$4) near3 memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 20:28
S58	163	S56 not S57	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 20:40
S59	95	microcontroller same (defect error fault fail$4) with table	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 21:25
S60	762	(714/42).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 21:26
S61	432	S60 and (disk disc)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 21:26
S62	18	S60 and (disk disc) and microcontroller	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 21:37
S63	170	S60 and (disk disc) same (defect error fault fail$4) with (table log stor$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/05 21:37

S64	122	S60 and (disk disc) same (defect error fault fail$4) near4 (table log stor$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/05 21:37
S65	107	S60 and (disk disc) same (defect error fault fail$4) near3 (table log stor$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/05 22:22
S66	2	("6829206").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/05 22:22
S67	10098	memory with test$4 with (defect fault error fail$)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:04
S68	5315	memory near3 test$4 with (defect fault error fail$)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:04
S69	181	memory near3 test$4 with (defect fault error fail$) with (log list table)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:11
S70	2	("6477672").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:36
S71	1251	microcontroller same test$4 same memory and external	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:37
S72	593	microcontroller same test$4 with memory and external	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:37
S73	383	microcontroller same test$4 with memory and external and normal	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:38
S74	7	microcontroller same functional with test$4 with memory and external and normal	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:41

S75	109	microcontroller and functional with test$4 with memory and external	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:43
S76	4	microcontroller and functional with test$4 with memory same (defect error fault fail$4) with (table map log list location) and external	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:59
S77	3	microcontroller and functional with test$4 with memory same (defect error fault fail$4) near4 (table map log list location) and external	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:43
S78	111	microcontroller and test$4 with memory same (defect error fault fail$4) with (table map log list location)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 14:46
S79	15323	(self-test "self test") not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:00
S80	2459	(self-test "self test") with memory not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:00
S81	333	(self-test "self test") with memory with (defect fault error fail$4) not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:01
S82	0	(self-test "self test") with memory with (defect fault error fail$4) near4 (bit-map) not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:02
S83	333	(self-test "self test") with memory with (defect fault error fail$4) not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:02
S84	17	(self-test "self test") with memory with (defect fault error fail$4) same (bit-map "bit map" log report list map) not BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:22
S85	42	(self-test "self test") with memory with (defect fault error fail$4) same (bit-map "bit map" log report list map)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/03/06 15:40

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S86	197	(714/44).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:41
S87	328	(714/31).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:41
S88	0	("020or21").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:41
S89	524	S86 or S87	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:41
S90	452	S89 and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:41
S91	170	S89 and memory with test$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/06 15:42